Nanoscale Optoelectronic Characterizations of Microstructured Thin-Film Solar Cells

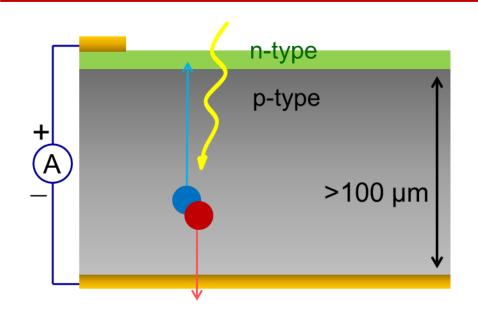


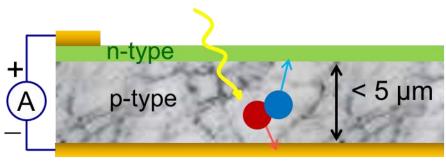
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Thin film PV uses inexpensive materials.



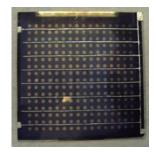


- c-Si solar cell
- Thick (indirect band-gap)
- High purity (large L_{n, p})
- High efficiency, but expensive

- px-CdTe, CIGS, CZTS(Se)
 - Thin (direct band-gap)
 - Highly defective (grains, GBs)
 - Flexible (e.g., metal foil substrate)
 - Relatively high efficiency
 (→ can be improved more)

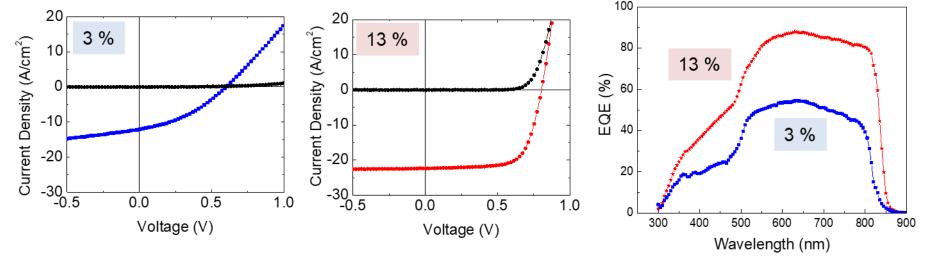


EQE (1 sun illumination) reflects J_{sc} .



CdTe solar cells fabricated by magnetron sputtering system*

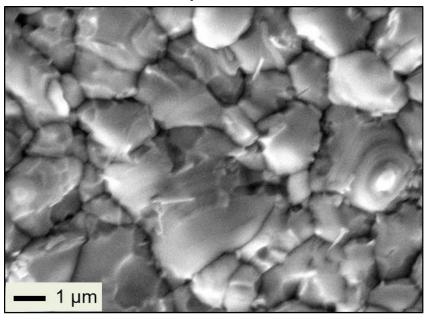
η (%)	$V_{oc}(V)$	J_{sc} (mA / cm ²)	FF (%)	R_S (Ω cm ²)	$R_{SH} (\Omega \text{ cm}^2)$
13.2	0.801	23.5	70	3	1650
3.0	0.605	13.0	38	20	260



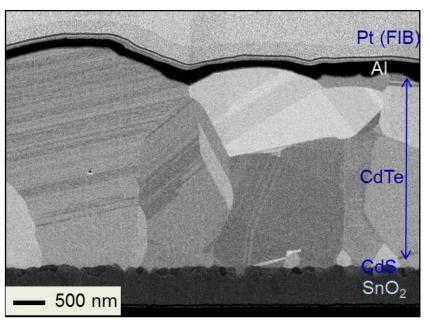
- CdTe absorber of 3 % device is highly resistive.
- EQE analysis shows carrier collection efficiency in each layer and interfaces.

The microstructure of CdTe is <u>not</u> homogeneous.

top view



cross section



- Comprised of grains (a few µm in size): lots of grain boundaries (GB)
- Local variation of chemical composition, defects
- Inhomogeneous (photo)current
- → impact of GBs on efficiency mainly unknown

Need for metrology to access properties of individual GB / GI (grain interior)



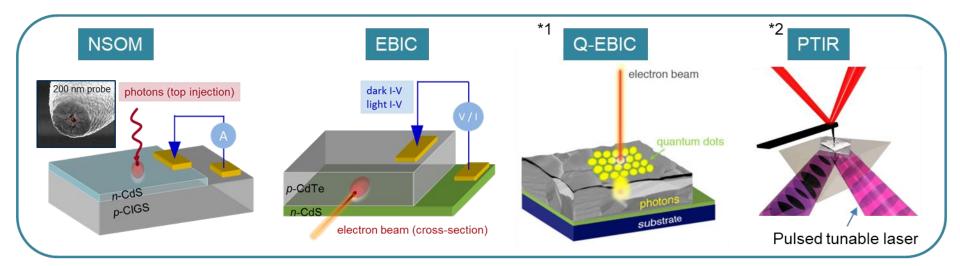
Techniques for Local PV Characterizations

✓ Local Probe

- Nanocontacts + nanoprobe
- Scanning probes
- Cathodoluminescence
- Photo-thermal induced resonance

Local Excitation

- Electron beam
- Near field optical source
- Ebeam + QD → photons (down-conversion)



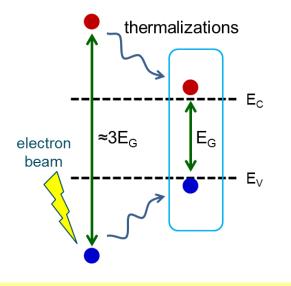
- ✓ Sample prep: plan view / cross-section / wedge / lamella / nanocontacts
- ✓ Correlation with structural / compositional properties (TEM, EDX, EBSD, XRD)
- ✓ Modelling

*1. H. Yoon *et al.*, AIP Advances (6), 062112, 9 439 (2013)



Electron beams generate EHPs → EBIC

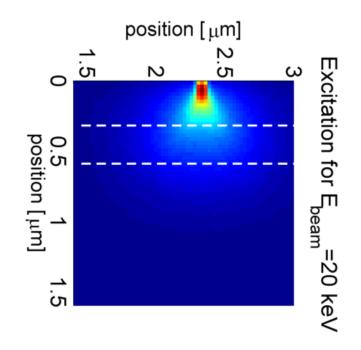
(1) I_{beam} → generation rate of EHP



 $(\# \text{ of EHPs}) \approx \frac{\text{(deposited e-beam energy)}}{3 \times \text{(energy band-gap)}}$

e.g. CdTe: E_G =1.5 eV, V_{beam} = 10 keV (BSE ≈30 %) ⇒ ≈1600 ehp

(2) V_{beam}→ generation bulb size

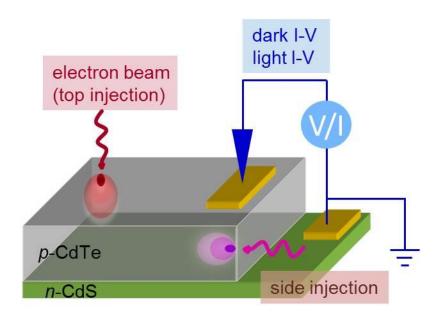


EBIC: Electron Beam Induced Current

EBIC is an ideal technique for systematic study of local carrier dynamics.

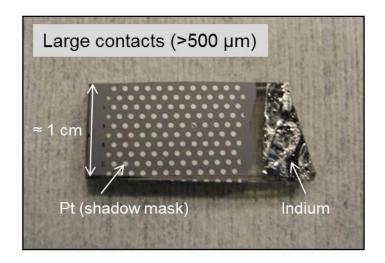


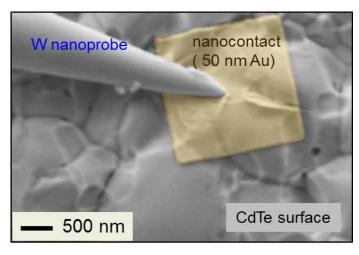
EBIC for Grain / Grain Boundary Characterizations



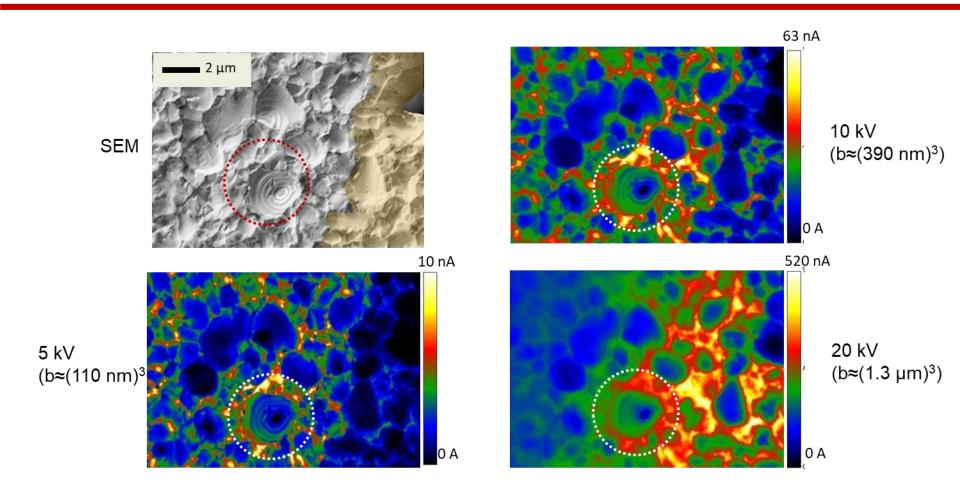


- Local carrier generation (bulb size: 110 nm to 1.5 µm in CdTe)
- Nano-contacts at grain boundary / grain bulk
- Probe PV properties of individual grains





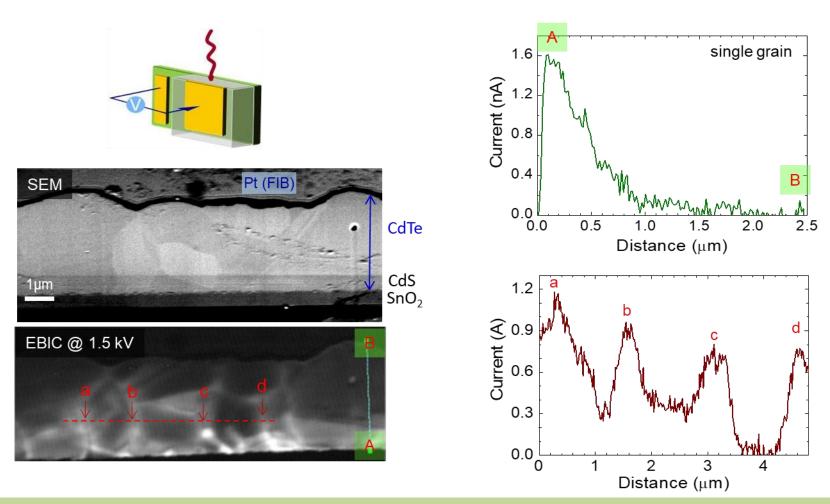
Spatial resolution < 100 nm with low keV



- High keV increases signal-to-noise ratio, but lower the spatial resolution.
- Higher collection at grain boundaries



Carriers are collected efficiently at GBs in CdTe.

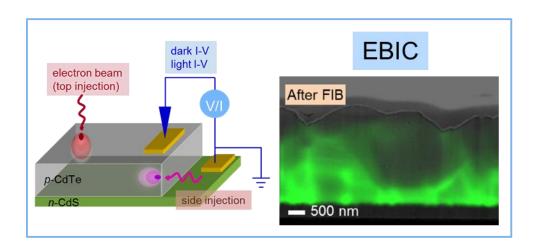


- Smooth surface was prepared by FIB.
- Grain boundaries in CdTe collects carriers more effectively than grain interiors.



Summary

- Physics of thin film PV is important and exciting.
- ✓ EBIC allows qualitative AND quantitative characterization of PV materials
 - Deconvolution of EBIC signal provides material parameters
 - Surface effects in EBIC are strong at the depletion region (and GB?)
- ✓ In progress: correlating local properties to overall device performance (electrical, optical, chemical, structural properties)





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Research participants / collaborators

- CdTe solar cell (U. Toledo)
- CIGS solar cell (U. Toledo)
- CZTS solar cell (DuPont)
- Si solar cells: epi Si, high-efficiency PV (NREL)

Thank you for your attention!